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Revisiting point defects in ionic solids and semiconductors

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The study of point defects in non-metallic crystals has become relevant for an increasing number of materials applications. Progress requires a foundation of consistent definitions and terminology. This comment clarifies the underlying definitions of point defects, encourages the correct use of relative charge for their description, and emphasises their recognition as quasiparticles.

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To the layman and to the newcomer, the word "defect" has only unpleasant connotations. Defects are bad, always undesirable. If unavoidable, their number should be minimised. To those who study defects in crystals, however, the word has various connotations. In some cases, defects are detrimental, but in many others, they are beneficial or even essential, imparting function to 'functional' materials. The layman's reductive standpoint of "bad" defects is thus replaced by the defect scientist's detailed, nuanced picture of detrimental or useful defects.

Interest in the "defect" picture has flourished in recent years, principally in terms of defect studies in myriad new systems, but also in terms of defect studies with new experimental and computational methods. And yet, and perhaps inevitably, the interest is accompanied by developments that tend to blur rather than illuminate some part of the picture. This comment reviews and refines certain fundamental aspects of point defects in ionic solids and semiconductors, in order to counteract three unwelcome developments: a lack of awareness of how defects are defined, a lack of awareness of why defects are defined, and a lack of awareness of how defects can be described in a concise and unambiguous manner.

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20 The increasing importance of point defects

The burgeoning interest in defects can be readily understood by considering the applications for materials in which defects, either by design or unintentionally, determine the performance. Not so long ago, materials with large defect concentrations, often referred to as non-stoichiometric compounds, were only found in a handful of niche applications, the most widespread arguably being potentiometric sensors in automotive exhaust systems. In recent years, the situation has changed dramatically. Nonstoichiometric compounds have fully permeated our society. Li-ion batteries with their intercalation electrodes, having revolutionised portable electronics, are set to reform automotive transport and can

now be readily found in applications from bicycles to power tools. The future will require materials with 1 2 defect-determined properties to play an even larger role, if pledges in line with the Paris Agreement are to be met. Hydrogen production at-scale is needed within the next 30 years (at most) in order to 3 decarbonise fertiliser, steel and cement manufacturing, and electrolyser cells based on oxide-ion 4 conducting solids are one of the foremost technologies capable of achieving this¹. Replacing thermal 5 power plants with photovoltaics is also required for decarbonisation, and hybrid-perovskite cells, already 6 offering advantages in terms of processing simplicity, are now challenging Si-based cells on efficiency²; 7 device performance and lifetimes are limited, however, by defect-dependent phenomena^{3,4}. Even in 8 computing, as the physical limits of Si-based MOSFET technology are pushed after more than 60 years 9 of miniaturisation, memristors based on the field-driven migration of ionic defects may usher in a new 10 wave of advanced programmable logic devices and physical neural network-based computing^{5,6}. In other 11 words, it is looking increasingly likely that many of the developments in transport, energy, and 12 computing over the coming decades will stem from our ability to manipulate the type, number and spatial 13 14 distribution of point defects in non-metallic crystals.

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16 **Definition, Terminology and Rationale**

Definitions constitute a cornerstone of a discipline by providing, first and foremost, a common language.
In the case of defects, this cornerstone often seems to be overlooked, and consequently without the
shared vocabulary, it is sometimes unclear if we are all talking about the same thing.

Defects are generally defined by subtracting an ideal (or reference) crystal from a real crystal: defect = 20 real - ideal. For point defects this definition reveals deviations from the ideal structure of non-metallic 21 crystals that can be divided into missing ions (termed vacancies), additional ions (termed interstitials), 22 foreign ions (termed dopants or impurities depending on the context; and situated substitutionally or 23 interstitially), and native ions sitting on the wrong site (termed antisites). Point defects can also be 24 identified from thermodynamics, namely as any atomic entity that adds to the configurational entropy of 25 the ideal crystal. Importantly, this second definition shares key features with the first definition: it also 26 requires a reference state; it is also formulated in terms of a difference; and it yields the same entities 27 (vacancies, interstitials, etc). 28

This brings us on to the question of why we define defects. This simple answer is because we have to. 1 The pioneering work of Frenkel, Schottky, Wagner and Jost in the 1930s^{7–13} revealed that at finite 2 temperature a perfect crystal is thermodynamically unstable: Point defects are an equilibrium component 3 of crystals. Indeed, chemical potentials can be defined for point defects (as building units), and this 4 permits chemical reactions involving point defects to be formulated (which thus established the field of 5 defect chemistry). A second answer to the question of why we define defects is that it is extremely 6 useful^{14–17}. Or to put it in a way that is rarely appreciated: point defects are quasiparticles. At the level of 7 nuclei and electrons, or even at the level of ions, solids are complex many-body systems, and quantitative 8 treatments of their properties rapidly become intractable if the descriptions are conducted at the level of 9 the constituent particles. By defining quasiparticles, we greatly simplify quantitative treatments. The 10 most well-known quasiparticle is the electron hole in a semiconductor. Rather than considering all the 11 electrons in the material's valence band, we focus on those electrons that are missing. Point defects are 12 quasiparticles because, as with other quasiparticles, they do not exist outside of the crystal, they obey 13 Fermi–Dirac statistics, and their definition allows for quantitative treatments of materials' properties. 14 Instead of treating a huge number of strongly interacting ions, say, we focus on a drastically smaller 15 number of point defects, which may be non-interacting in the simplest case, or if they do interact, can be 16 treated through pair-wise rather than multi-body interactions. We define point defects, therefore, for 17 necessity and for simplicity. 18

Another cornerstone of a discipline is the consistent use of terminology to ensure that entities under discussion adhere to the basic definitions. In this case *crystalline* or *crystallographic point defects* is the term used. This distinguishes such entities from higher dimensional or extended crystalline defects, such as dislocations and grain boundaries, as well as from defects in amorphous structures (as discussed below). In most cases, as we do here, the term *point defect* is used as an abridged form. Unfortunately, in some instances this leads to ambiguity and confusion, with claims of "defect-free" materials (not thermodynamically stable at finite temperatures).

The word 'defect', as we noted above, has unpleasant connotations in general; its alternatives (imperfection, flaw, mistake, error, blemish) are hardly an improvement. It is tempting, therefore, to suggest that an entirely new term should be used. While this might seem radical, it would not be

unprecedented. The word 'hole' was originally used to describe a missing atom within a crystalline
material before it was appropriated in the 1940s (during the development of semiconductor electronics)
to describe an electron missing from the valence band. A new word was required to fill the hole (pun
intended) and 'vacancy' became the agreed-upon term¹⁸. Replacing the word 'defect', however, would in
our view be fundamentally misguided. Crystal defects are defects. Using a different word would only
provide a superficial veneer; and it would entail, arguably, a shift in focus away from the underlying
definition.

Based on both definitions given above for identifying crystalline point defects, it would appear that there 8 can be no point defects in an amorphous material because there is no uniquely defined amorphous 9 reference structure and hence no unambiguous method for identifying deviating atomic entities. 10 Alternatively, from the point of view of a reference crystal, the entire amorphous material is, essentially, 11 a crystalline defect. That said, electronically active centres are known in many amorphous 12 semiconductors (and associated with dangling bonds)^{19,20}. In addition, there are amorphous materials for 13 which a topological treatment yields atomic-scale deviations²¹. Such approaches are unlikely to apply to 14 15 all amorphous materials, however, in the way that the point-defect definitions are universal to all crystalline solids. Furthermore, applying different approaches to an amorphous system may not 16 necessarily identify the same species (cf. the two different definitions for point defects that both yield the 17 same species). Consequently, it may be more helpful to use different terms for defects in amorphous 18 19 materials: vacancy-like or quasi-vacancy and interstitial-like or quasi-interstitial are reasonable possibilities²², but completely different names would perhaps be more appropriate; in any case, vacancies 20 and interstitials should be reserved for crystals. Certainly, point-defect notations that indicate a 21 crystallographic site (see below) should be avoided in the case of amorphous materials because a 22 reference crystal will not have been used to identify deviating atomic entities. Lastly, we note that 23 defining point defects in crystals is not simply an academic exercise: it has unquestionable and 24 demonstrable benefits. One should ensure that this is also the case when defining defects in amorphous 25 systems. 26

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1 Defect notation and defect charge

A notation is used to convey specific information in a concise, unambiguous form. Writing Ca^{2+} , for 2 3 example, conveys that a particular chemical element in a specific charge state is being considered. In the case of point defects, the definitions described above (with respect to an ideal structure) demand a 4 different notation, as does the need to distinguish defects from conventional chemical species. Various 5 notations have been proposed^{23,24} over the years, but it is the notation derived by Kröger and Vink²⁵ that 6 has established itself almost universally. It consists of a main symbol, indicating the chemical species, 7 the electronic species (e is used for an electron and h for an electron hole) or a vacant site; a subscript, 8 indicating the site in the crystal or an interstitial site; and a superscript indicating the relative charge (* 9 for neutral, for relative positive charge, and for relative negative charge), or more seldom, the real 10 charges (⁰ for neutral, ⁺ for real positive charge, and ⁻ for real negative charge). 11 Standard Kröger–Vink notation uses V for a vacancy and I for an interstitial site. This is clearly 12 problematic because it leads to confusion with the chemical elements vanadium and iodine. Norby²⁶ 13 proposed to remove these ambiguities by using lower-case symbols, v for a vacancy and i for an 14 interstitial site. The benefits are easily recognised by considering, as Norby suggested, point defects in 15 vanadium iodide. In the standard notation, V_I is not unambiguous, for it could be one of four species; in 16 Norby's version, the four species are clearly identified: v_I (an iodine vacancy), V_i (a vanadium 17 interstitial), v_i (a vacant interstitial site) and V_I (a vanadium antisite defect on an iodide-ion site). 18 As mentioned above, the burgeoning interest in defects has led to some unwelcome developments. One 19 20 such development is the use of O_V to indicate v₀ or of I₀ to indicate O_i (focussing on anion defects as examples). In addition to being in conflict with the standard (Kröger–Vink) notation, this approach 21 relegates the most immediately important information, the species being described, to the subscript. This 22 relegation creates further confusion when discussing substitutional or antisite defects. For example, Gd 23 sitting on a Zr site would have to be written as Zr_{Gd} rather than Gd_{Zr} to be consistent, which is needlessly 24 confusing to the reader. 25

The second unwelcome development is the use of real charge to indicate relative charge. This is wrong because they are two different quantities: the former is defined relative to free space; the latter, relative to a crystal lattice (see above). And since there is a difference, the symbols used to indicate relative charge

- 1 have to be different to those used to indicate real charge, otherwise there is the possibility of ambiguity,
- 2 or worse, error. In order to make the difference clear, we consider in the following an oxide crystal, in
- 3 which either O^{2-} , O^{-} or O has been removed from a regular O^{2-} site. (NB: In talking about real charges we
- 4 use for good reason²⁷ the nominal charge of the ions; and similarly, for the relative charge of defects.)



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The removal of these three O species generates the defects, in Kröger–Vink notation, v_0^{\cdot} , v_0^{\cdot} and v_0^{\times} . In terms of real charge, these same three species are v_0^0 , v_0^- and v_0^{2-} . Both descriptions indicate the same

Fig. 1 | Describing point defects with real charge or relative charge. Three different charge states of 6 an oxygen vacancy in a metal oxide MO are shown with their real charges or their relative charges (in 7 Kröger-Vink notation^{25,26}). One benefit of the relative-charge description is that the relevant entities (the 8 quasiparticles) are immediately apparent. Another benefit is that the response of defects to an applied 9 electric field is also immediately apparent: $v_0^{"}$ and $v_0^{'}$ move; v_0^{\times} and 0_0^{\times} don't, as they are neutral. If real 10 charges are used, the treatment needs to include O_0^{2-} , as well as v_0^0 , v_0^- and v_0^{2-} , and motion is restricted 11 to those ions that have a neighbouring vacancy in the direction of ion drift. After careful consideration, 12 O_0^{2-} jumping to v_0^0 is found to constitute charge transport, whereas O_0^{2-} jumping to v_0^{2-} does not. By 13 using real charges rather than relative charges, we obtain the same information but we spurn one of the 14 benefits of defining defects — the simplicity of the treatment. 15 16

information: an oxygen site missing an oxygen atom and missing 2, 1 or 0 electrons (Figure 1). The use 1 of real charge to indicate relative charge, i.e. v_0^{2+} , v_0^+ and v_0^0 to indicate v_0^{\cdot} , $\dot{v_0}$ and v_0^{\times} , should be 2 avoided because, besides being inconsistent with how defects are defined (defect \neq real – ideal, see 3 4 above), it fails as a notation: It does not convey information correctly. By using a real charge to indicate a relative charge, it gives neither the correct real charge nor the correct relative charge. In fact, taken at 5 face value, v_0^{2+} denotes a site at which one oxygen atom and four electrons have been removed, whereas 6 what the writer of v_0^{2+} wants (but fails) to indicate is a site missing one oxygen atom and two missing 7 electrons. 8

Indicating the correct relative or absolute charge of defects is also important because defects can change 9 their charge state by trapping or de-trapping electronic species. Taking the examples of isolated anion 10 and cation vacancies in the oxide MO, we have v_0^{\times} donating one electron (e') to the conduction band to 11 become $\dot{v_0}$, and then a second to become $\ddot{v_0}$ (oxygen vacancies are donor-type defects); and v_M^{\times} 12 accepting one electron from the valence band (i.e. donating a hole) to become v'_M , and then a second to 13 become v_M'' (cation vacancies are acceptor-type defects). The energies of these reactions correspond to 14 energy levels within the electronic bandgap. These levels are correctly described as v_0^{\times}/v_0^{\cdot} and $\dot{v_0}/v_0^{\cdot}$ 15 transitions, and v_M^{\times}/v_M' and v_M'/v_M'' transitions. 16

Writing defect reactions with the wrong notation reveals a further problematic aspect. The anti-Frenkel
reaction in an oxide, written with relative charges, is

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$$0_0^{\times} + v_i^{\times} \rightleftharpoons v_0^{"} + 0_i^{"},$$

20 or with real charges,

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$$O_0^{2-} + v_i^0 \rightleftharpoons v_0^0 + O_i^{2-}$$

Both equations communicate the same information, and in most cases, the first equation will be preferable (see Figure 2). If we start, however, with v_0^{2+} (the wrong notation for an oxygen vacancy bearing a double relative charge), the charge-balanced reaction is $0_0^0 + v_i^0 \rightleftharpoons v_0^{2+} + 0_i^{2-}$. That is, we are forced to write on the reaction's left-hand side that an oxide ion sitting on its regular site has zero real charge, even as we imply through both oxygen defects on the right-hand side that the oxide ion is doubly charged. This problem is not restricted to the anti-Frenkel reaction. The reduction of an oxide to form electrons and oxygen vacancies reads: $O_0^{\times} \rightleftharpoons v_0^{\circ} + 2e' + \frac{1}{2}O_2$, in terms of relative charge; or $O_0^{2-} \rightleftharpoons$ $v_0^0 + 2e^- + \frac{1}{2}O_2$, in terms of real charge. The wrong version, $O_0^0 \rightleftharpoons v_0^{2+} + 2e^- + \frac{1}{2}O_2$, again requires an oxide ion sitting on its regular site to have zero real charge. A consistent, unambiguous defect notation avoids, therefore, the use of real charges to indicate relative charges.



cation anion electron vacancy

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Fig. 2 | Describing point-defect reactions with real charge or relative charge. Equivalent descriptions
 of anti-Frenkel disorder and oxide reduction in terms of real charges and relative charges. Again, one
 benefit of the relative-charge description is that the relevant entities (the quasiparticles) are immediately
 apparent.

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We have seen that point defects can be described unambiguously either with relative charge or with real charge. In most cases, relative charge is preferred, but not in all. Our recommendation is to use one or the other. Mixing relative and real charge will generally result in errors or cosmetic coverings of errors, in particular when writing defect reactions but also in other cases. For example, when considering the relaxation of ions surrounding an oxygen vacancy in an ionic crystal, it is sometimes incorrectly claimed that there is a repulsive interaction between the positively charged oxygen vacancy and the positively charged cations. This is incorrect because the defect has a *relative* positive charge whereas the cations

have a *real* positive charge. Avoiding the combination of real and relative charge, one readily finds that 1 2 there is no interaction: in terms of relative charge, the cations are neutral and the defect is charged, whereas in terms of real charge, the cations are charged, but the vacancy is neutral. The relaxation of the 3 cations away from the vacancy is in fact best understood in terms of real charge. From the direction of 4 the vacancy, the cations experience less Coulomb attraction (the oxide ion is missing), and this results in 5 the cations relaxing away from the oxygen vacancy. A second case for which the treatment in terms of 6 real charge is preferred is the transfer of species between two phases, e.g. between an electrolyte and an 7 electrode. 8

9 **Building on solid foundations**

The era of point defects started, arguably, close to a century ago, with Pohl's work on colour centres in alkali halides²⁸. Frenkel, Wagner, Schottky and Jost^{7–13}, through their contributions to point-defect thermodynamics and kinetics, put the subject on a firm foundation. The period from 1949 to 1959 has been called by Nowick¹⁸ a golden age in the development of concepts in crystalline defects, specifically because definitions crystallised and a notation²⁵ emerged. It is on these foundations that the interest in crystal defects grew continually over the intervening decades.

The coming years will undoubtedly witness a further increase. Even more people will be confronted with materials systems and devices, in which point defects play a central role. If progress is not to be hindered, a common language in terms of definitions, terminology, and notation is indispensable. Attention needs to be paid to the (reliable and consistent) foundations. Only in this way will we

- 20 accelerate developments, perhaps even ushering in a new golden age of point defects.
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